



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/705,814

Filing Date: November 10, 2003

Applicants: Shinichi Nakamura

Group Art Unit: 2861

Examiner: Nguyen, Lamson D

Title: METHOD OF DETERMINING ABNORMALITY OF
NOZZLES IN IMAGING APPARATUS; IMAGING
APPARATUS; ELECTROOPTIC DEVICE, METHOD OF
MANUFACTURING ELECTROOPTIC DEVICE; AND
ELECTRONIC EQUIPMENT

Attorney Docket: 9319H-000586

*Place
in file
07/05/06
A*

Mail Stop Non-Fee Amendment
Director of The United States Patent and Trademark Office
P.O. Box 1450
Alexandria, Virginia 22313-1450

AMENDMENT AFTER ALLOWANCE RULE 1.312

Sir:

In response to the Notice of Allowance dated March 29, 2006, please amend this application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 7 of this paper.